Manufacturing of High Rates Resistive Micromegas (RHUM* Project)

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[1]1267,08µm

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DRD1 Collaboration Meeting

18 June 2024 CERN

* Resistive High granUlarity Micromegas

Recent developments on resistive Micromegas

One-slide summary from Rui De Oliveira (<u>RD51 MPGD School</u> – December 2023)

All Resistive MM structures



<u>High-rate detectors 10Mhz/cm2</u> Charge evacuation inside active area



Recent developments on resistive Micromegas



M. Iodice – DRD1 – 2nd Collaboration Meeting – June 20, 2024

Double DLC layer Micromegas Concept

- Configuration inspired by G. Bencivenni and co-authors (applied to uRWell) (JINST 12 (2017) 06, C06027)
- Readout pads are covered by a double layer of DLC with a grid of staggered interconnecting vias for rapid charge evacuation → Charge evacuation inside the active area, through "vertical dots"
- First generation: Grounding connection vias "filled manually"
- Second generation: the sequential build up technique (SBU) was implemented exploiting copperclad DLC foils. It allows best alignment of vias and connections by plating techniques.
 Fully compatible with PCB manufacturing techniques (Rui De Oliveira at INSTR 2020)





Double DLC layer Micromegas Manufacturing

Rui's talk at INSTR 2020



Double DLC layer Micromegas Manufacturing

Rui's talk at INSTR 2020



CERN-INFN Sputtering Machine @ CERN

See Rui's talk today and G. Morello 1st DRD1 Collab Meeting

Currently in these weeks a CERN-INFN team is carrying on new tests.

Very advanced production of large foils of copper clad "DLC+"



The "bulkage" i.e. how to trap and sustain the mesh in the pillars

- The bulkage is a non-standard PCB process
- Needs manual work
- It is among the more expensive steps in the MM production.
- Simple in principle, however, faces significant challenges when applied to industrial contexts.



MATERIAL

- Photo imageable coverley was Pyralux → now Dynamask
- Stretched mesh:
 - Frames
 - Stretching process
 - Clean, high-quality mesh (18/45)

Our Production at CERN - Towards Large Area

6		
small size prototypes	medium size prototypes	large size prototype
x - 48 pads	MM400-1 MM400-2	new
active area : 4.8cm x	Two detectors Paddy400-1 and Paddy400-2	
4.0 Cm		"The Big one" Paddy-2000: 50 x 40 cm ²
segmented in 48 x16 readout pads	readout in central part)	Readout central region
pad size: 1 x 3 mm ²	Anode plane pad size: 1x 8 mm ²	6.4x6.4 cm ² with 1x8 mm ² pads
	also tested in sandwich config sharing the same cathode	Surrounding area – 2048 pads, 10x10 mm²

Taken from M. Biglietti's talk on Monday

Critical steps in the resistive bulk MM manufacturing

- High quality PCB manufacturing: easy to find at industry
 → caveat: Large size (multilayer) PCBs significantly reduce the market
- DLC with copper-clad: will be done "in house" with the magnetron sputtering machine available at CERN → more studies needed to launch production –almost got there!
- High quality mesh procurement and stretching on frames (huge experience at Institutes from ATLAS)

• "Bulkage"

For large productions (and for large requests of R&D prototypes) it is mandatory to:

- Transfer the technology of the most critical steps to the industry
- Keep the same level of quality/reliability/easy interaction as we are used with the MTP Workshop at CERN (very challenging!)
- Simplify, automatise, reduce the costs \$\$\$

A step-by-step approach towards complete production at <u>ELTOS</u> SpA has been initiated

Micromegas Manufacturing at ELTOS

Preparation

- Materials supplied by us :
- Design of the detector (Gerber files of PCB, DLC, coverlay, ..) Simplified version:
 - \circ 10 x10 cm² active area, pad-size: 1x8 mm²
 - o Single DLC foil without dot evacuation vias
- One roll of photo imageable material Dynamask foils 45 μm thick
- Stretched mesh on frames
- Patterned DLC foils







 \rightarrow Construction of two "identical" prototypes

June 11-13, 2024

M. Iodice – DRD1 – 2nd Collaboration Meeting – June 20, 2024

Micromegas Manufacturing at ELTOS

Main Steps of manufacturing at ELTOS

- PCB production^(*)
- DLC foil inspection measurement and gluing/pressing on the PCB
- Bulkage: Lamination of Dynamask + mesh, exposure, development
- Quality checks and Metrology



DLC Foils



Resistivity map

- Avg DLC1: 29 MOhm/sq
- Avg DLC2: 32 MOhm/sq

Glue lamination



Glue: Akaflex, thickness 25 μ m

DLC pressing



DLC positioned on the PCB







Pressing stack preparation with layers of: copper, conformable layer (pacoflex), cushions, ...

Sent to press and curing

DLC Foils



Resistivity map after pressing and curing:

- Avg DLC1: 38 MOhm/sq (was 29 → +30%)
- Avg DLC2: 36 MOhm/sq (was $32 \rightarrow +12\%$) (an increase is expected if DLC is not completely stabilised)



HV Connection with silver glue





Manual intervention. Can be simplified

BULKAGE – lamination with Dynamask

Dynamask thickness: 45 μ m \rightarrow 3 layers + mesh + top layer



Bulkage – UV exposure



Mask with patterned coverlay and circles for pillars in the active area

Exposure: 900 mJoule

Bulkage - development

Transport in a diluted soda Solvay bath







Bulkage – final curing









In the oven...



Metrology – a few examples

Estimate of the amplification gap size with the Keyence microscope



As expected, the nominal thickness of 3x45 = 135 um of gap shrinks to a lower value.

However, ~102 um (accounting for 18 um of wire thickness in woven mesh) seems a bit too low ! ...will investigate further



Metrology – a few examples

Estimate of the amplification gap size with metallography



As expected, the nominal thickness of 3x45 = 135 um of gap shrinks to a lower value.

A value of ~112 um is in line with expectations

(need to check the consistency of the two measurements – however we believe the metrology is a more accurate measurement)

Summary

- The production of Double-Layer DLC Resistive Micromegas at CERN has reached an established high-quality standard and reliability, even for large sizes.
- Due to the large number of requests, the MPT Workshop is experiencing extended delay times.
- R&D of new configurations can hardly be done outside CERN.
- For large-scale production, the cost of this technology needs to be reduced.
- The transfer of manufacturing technology to industries is essential.
- After the experience gained with ATLAS production, ELTOS S.p.A. is in a good position to face new, more complex productions (including bulk).
- The tests carried out at ELTOS last week are promising. ELTOS is interested in our developments, and we need to strengthen this collaboration, progressing towards large-scale and full industrial production.

Thank you!

Additional Material

The start (2015): Resistive Pad-Patterned Micromegas

- Configuration inspired by (1 cm² pad resistive MM) by M. Chefdeville and co-authors [1], [2], and by (non-resistive GEM + MM hybrid) detector in COMPASS [D. Neyret, et al.]
- Push the technology to high rates Main changes/improvements:
 - Combine a resistive scheme to a high granularity readout for stable operation at high gain (G~10⁴ and beyond) and high rates (up to 10 MHz/cm²)
 - o Improve and ease the production technique



The Resistive Pad-P Micromegas - manufacturing

(see Rui's talk at INSTR 2020 and slide in backup)

- First Prototype: Full screen-printing (including the insulation layer)
 → failed due to sparks caused by (unavoidable?) micro-holes in the insulation layer;
- Second generation: 2 layers screen printed resistors on Kapton → partially successful: for small pads, the embedded resistors are difficult to shape with high enough resistance
- Third generation: a "MIX" technique was adopted: the screen printing is still used for the top layer while the embedded resistors were obtained by patterning a DLC layer on Kapton Thanks to the higher resisivity of DLC (O(MΩ/sq)) with respect to the screen-printing paste (around 10 kΩ/sq), this solution allows for easier patterning of small pads with high resistance
- →This is the solution adopted to build our latest PAD-Patterned detector

Excellent results in terms of stability Not fully satisfactory for some performance results

(see M. lodice - RD51 <u>https://indico.cern.ch/event/1327482</u>)



Printed Pad-Patterned with embedded resistors

Rui's talk at INSTR 2020

